

Counting Electrons for Metrology of Electrical Currents

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SI base unit: ampere (A)

The ampere, is the SI unit of electric current.
It is defined by taking the **fixed numerical value of the elementary charge $e = 1.602\,176\,634 \times 10^{-19} \text{ C} \dots$**

All electrons carry the same charge.

Mise en pratique:

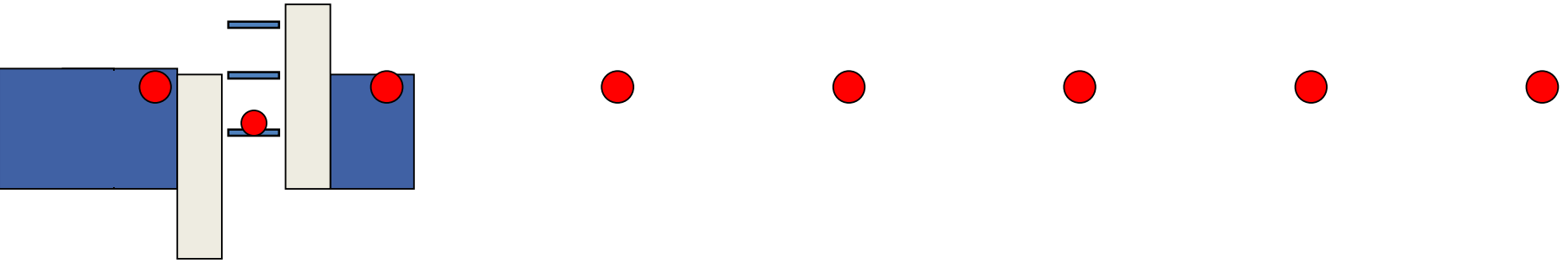
The Ampere can be realized by...
using a single electron transport (SET)
or similar device...



→ Count electrons to measure current.

Single Electron Pumps (SEP)

$$I = nef$$

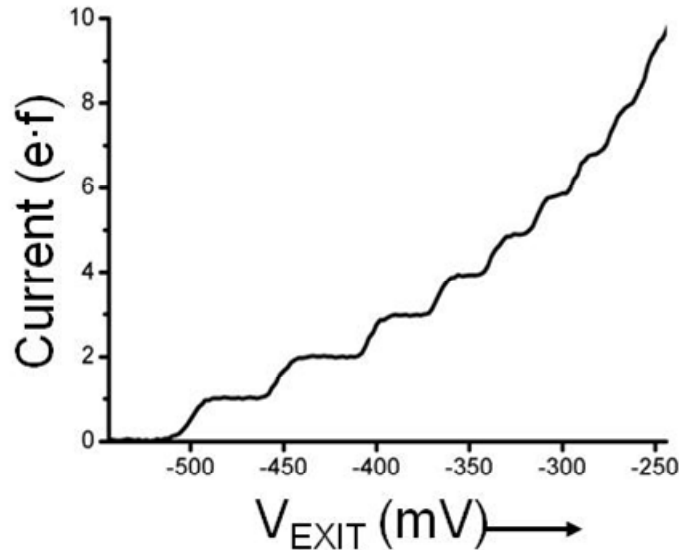


□ Direct realization of the SI ampere

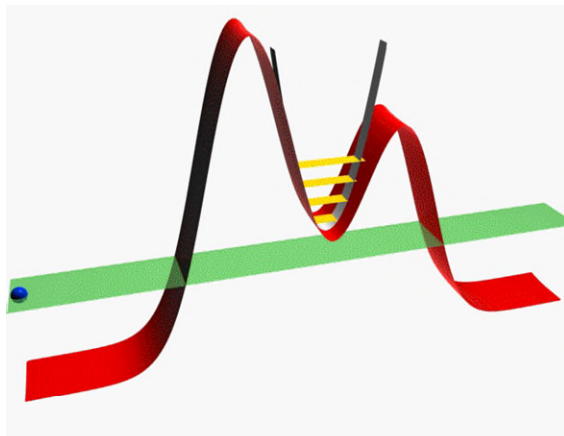
□ Challenges:

- Frequency as large as possible, e.g., $f = 1$ GHz, $I = 160$ pA (for $n = 1$)
- Low uncertainty, at least smaller than the uncertainty of the ampere realization in the old SI ($\approx 3 \times 10^{-7}$)

Semiconductor single electron pumps



- GaAs/AlGaAs quantum dot
 - Charging energy $E_C \sim \text{meV}$
 - Modulation of entrance barrier
 - Capture electron from source
 - Eject to drain
 - Quantised current: $I = e \cdot f$
-
- Advantage:
 - High frequency $\rightarrow$ high currents
 - Simple fabrication
 - Low error rate

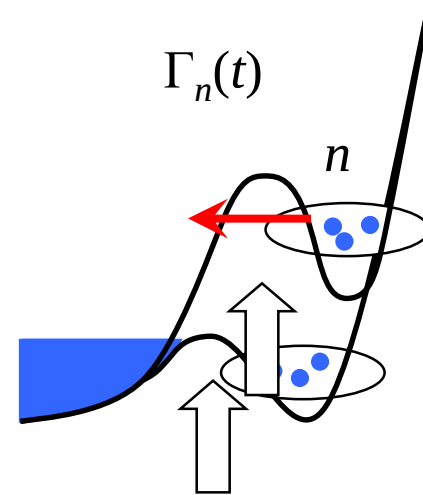


But:

- Tunnelling is **stochastic**
- Rare **pump errors** need to be **controlled** or **counted**

Decay cascade model

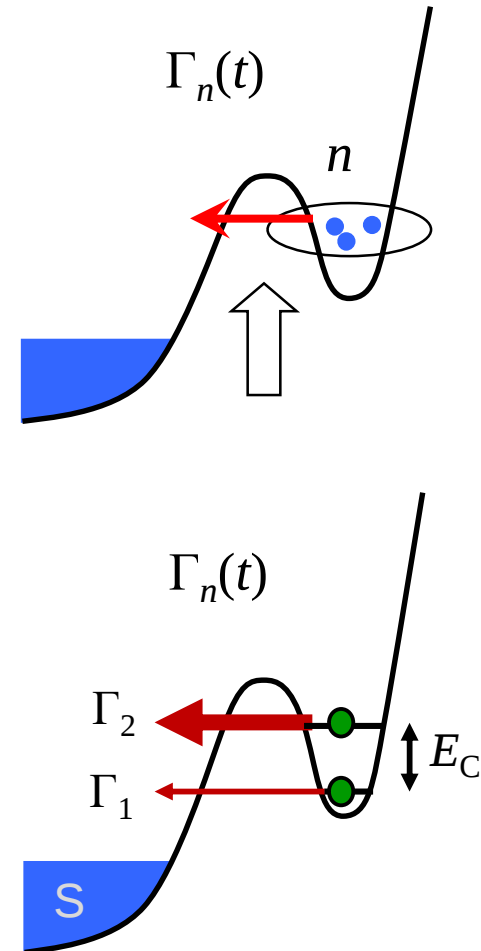
- What happens when the barrier is raised?
- Barrier *and* dot rise
→ excess electrons tunnel back



Decay cascade model

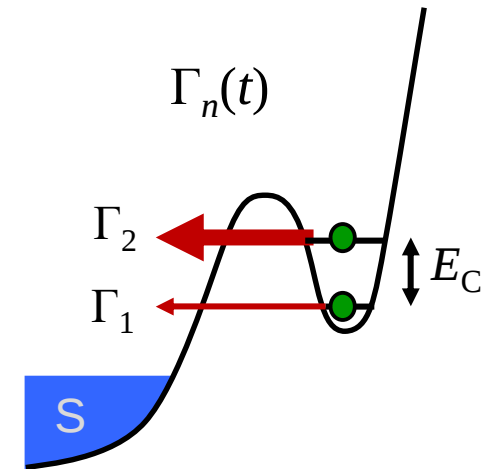
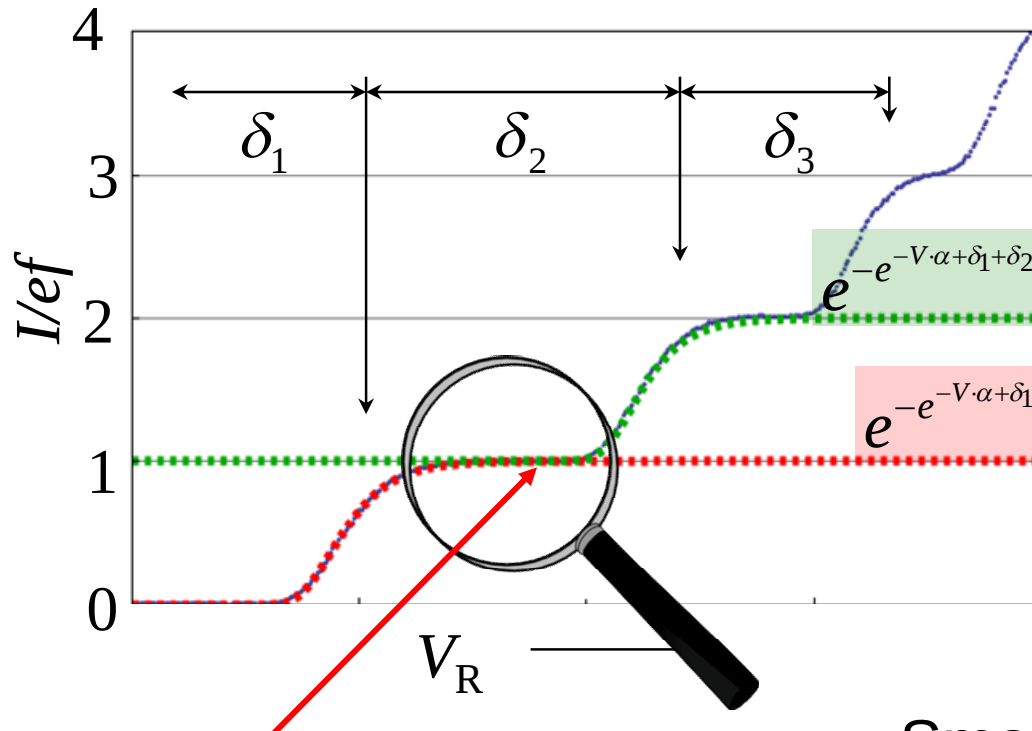
- What happens when the barrier is raised?
- Barrier *and* dot rise
→ excess electrons tunnel back
- Barrier more transparent for higher electron number
- Higher electrons tunnel back faster than lower electrons
- Predicts double exponential curve for each level

$$I(V) = e^{-e^{-V \cdot \alpha + \delta}}$$



How do we get a good pump?

Decay cascade model predicts error rate P_{err} at sweet spot

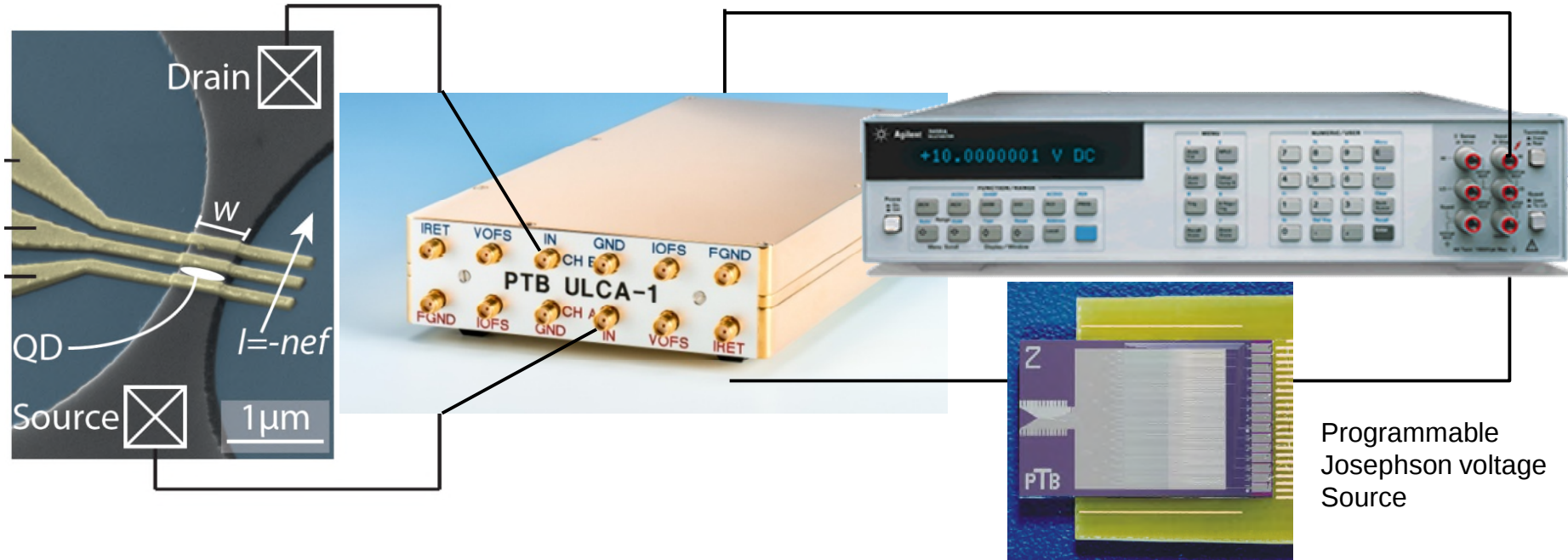


$$P_{err} \sim \exp \left(- \left[\ln \frac{\Gamma_2}{\Gamma_1} \right] \right)$$

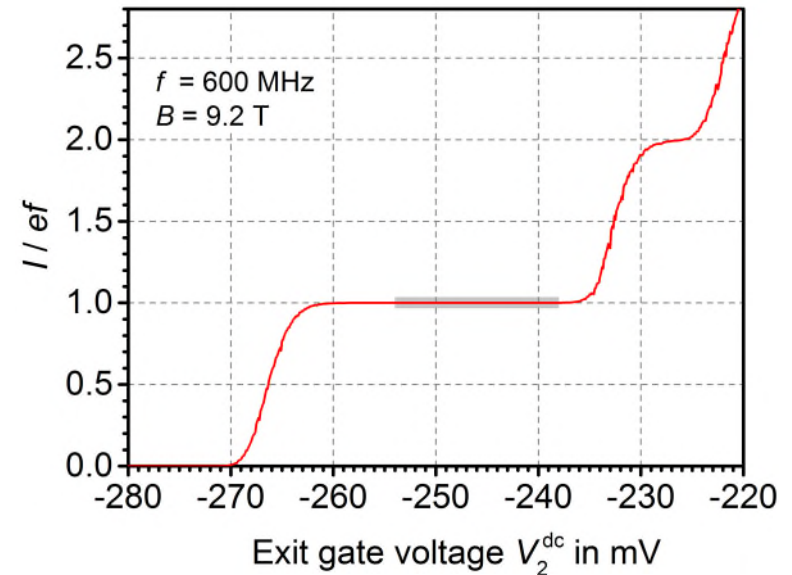
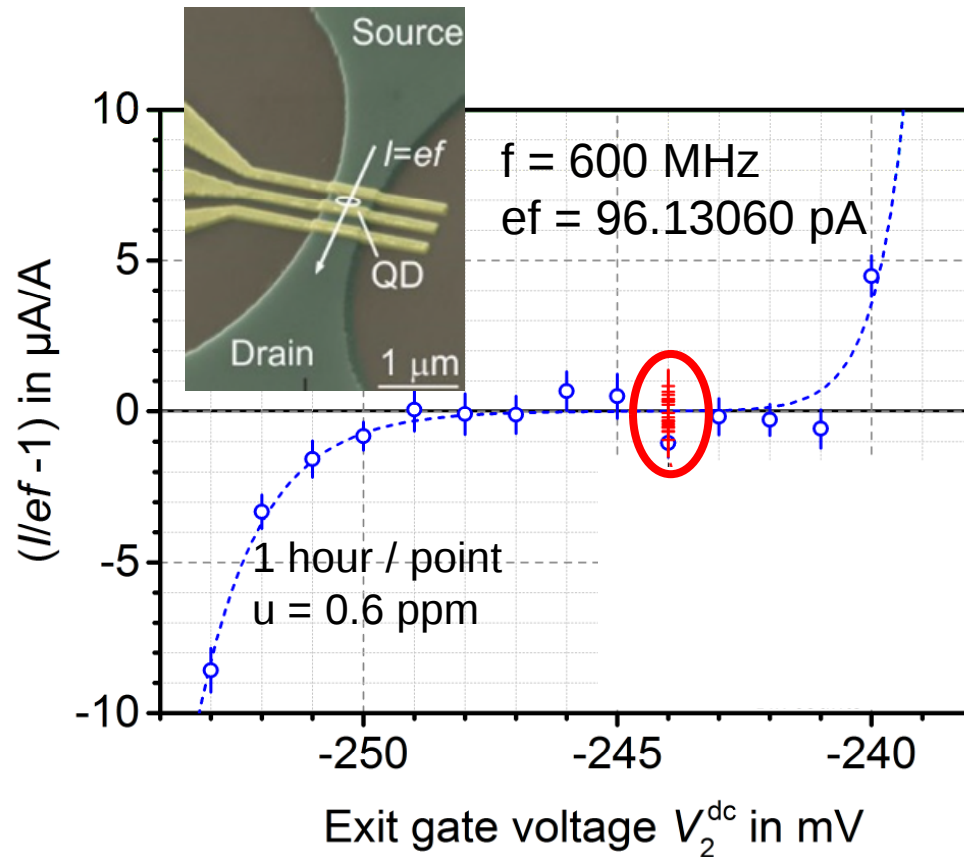
Smaller dot $\rightarrow$ larger E_C

$\rightarrow$ larger $\frac{\Gamma_2}{\Gamma_1} \rightarrow$ better pump!

Traceable measurement of SEP output current



Single-electron pump verification



21 hour measurement at
working point $V_2 = -244 \text{ mV}$

Deviation from ef :

$0.10 \pm 0.16 \text{ ppm}$

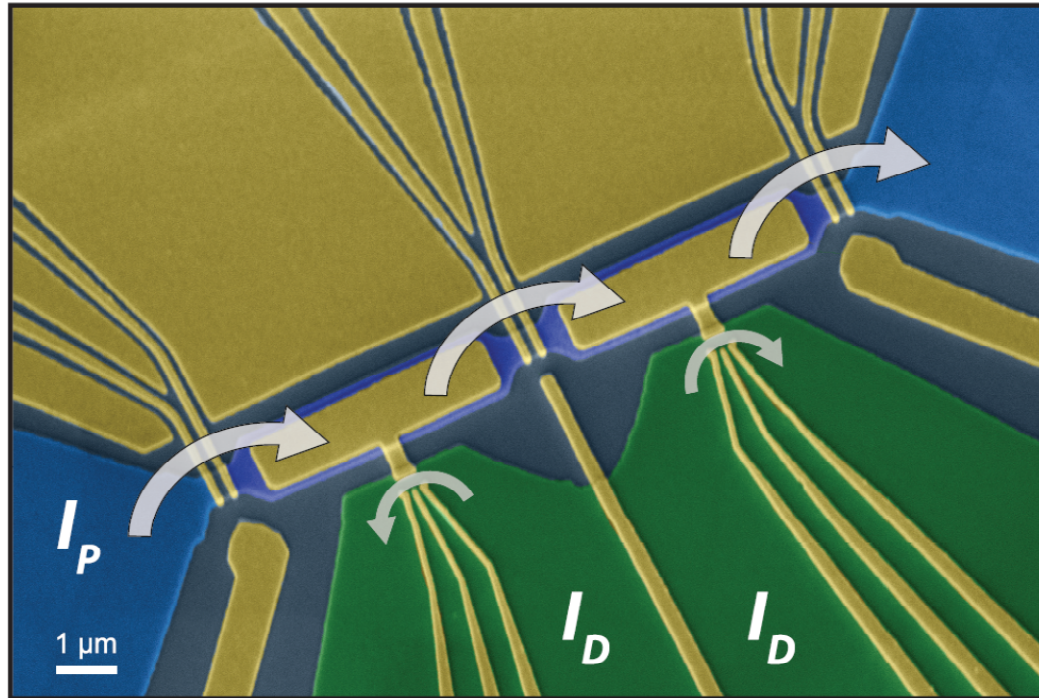
(total uncertainty)
< 100 electrons/s

SEP quantization **verified** with better
accuracy than Ampere realization
in the old SI

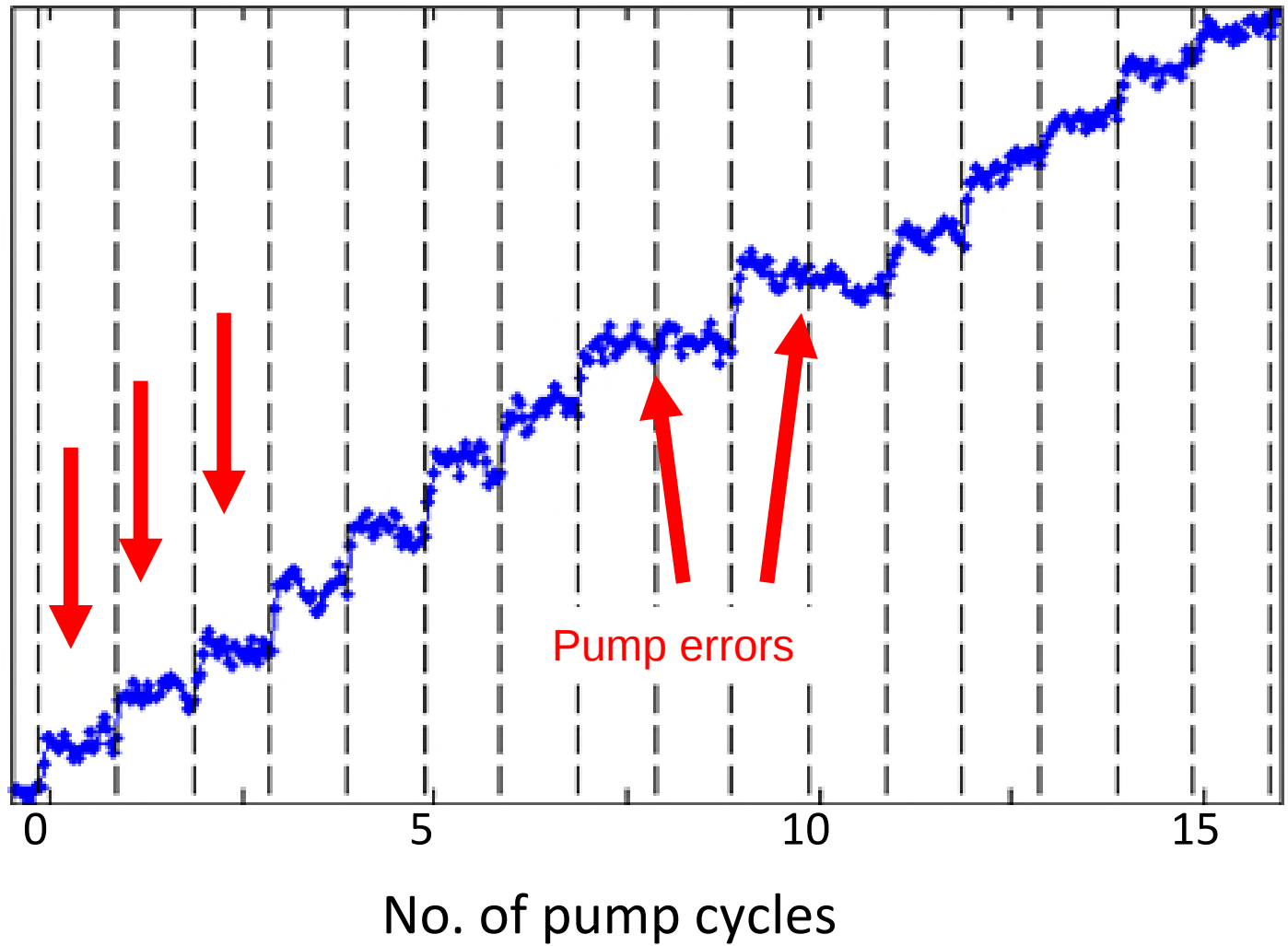
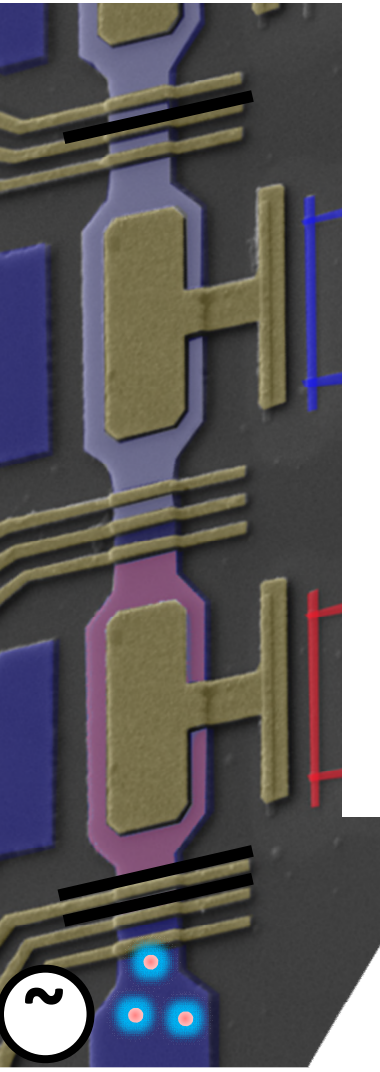
F. Stein et al. APL 2015
ibid. Metrologia 2016

Detection of pumping errors

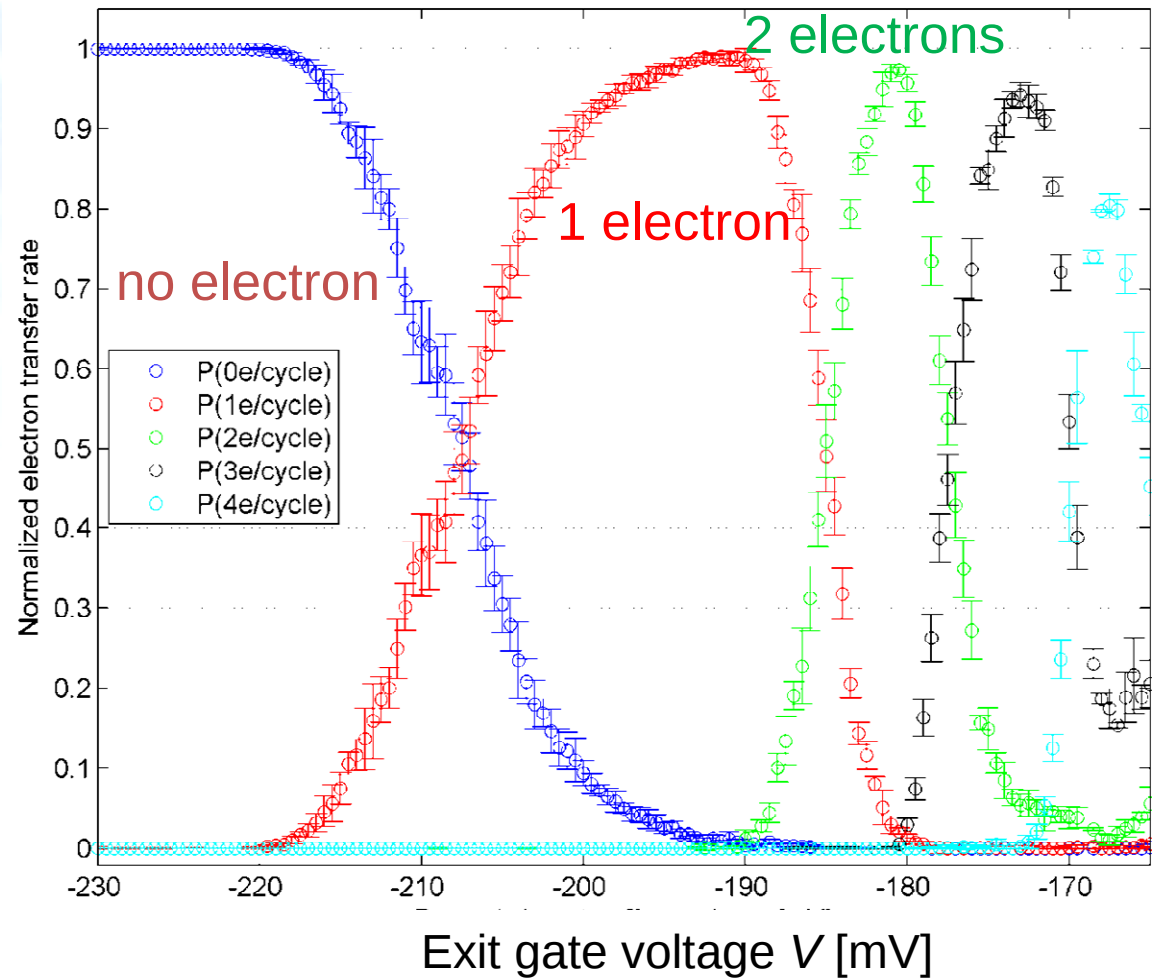
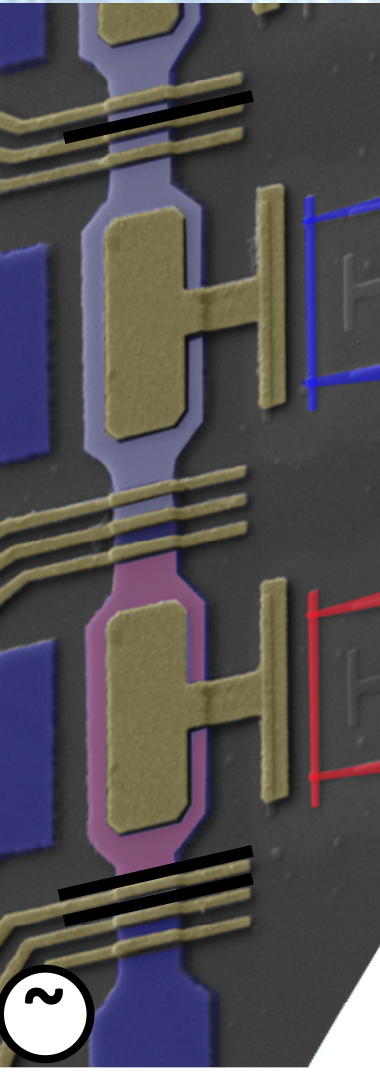
- Serial connection of single electron pumps
- Single charge detection on connecting nodes

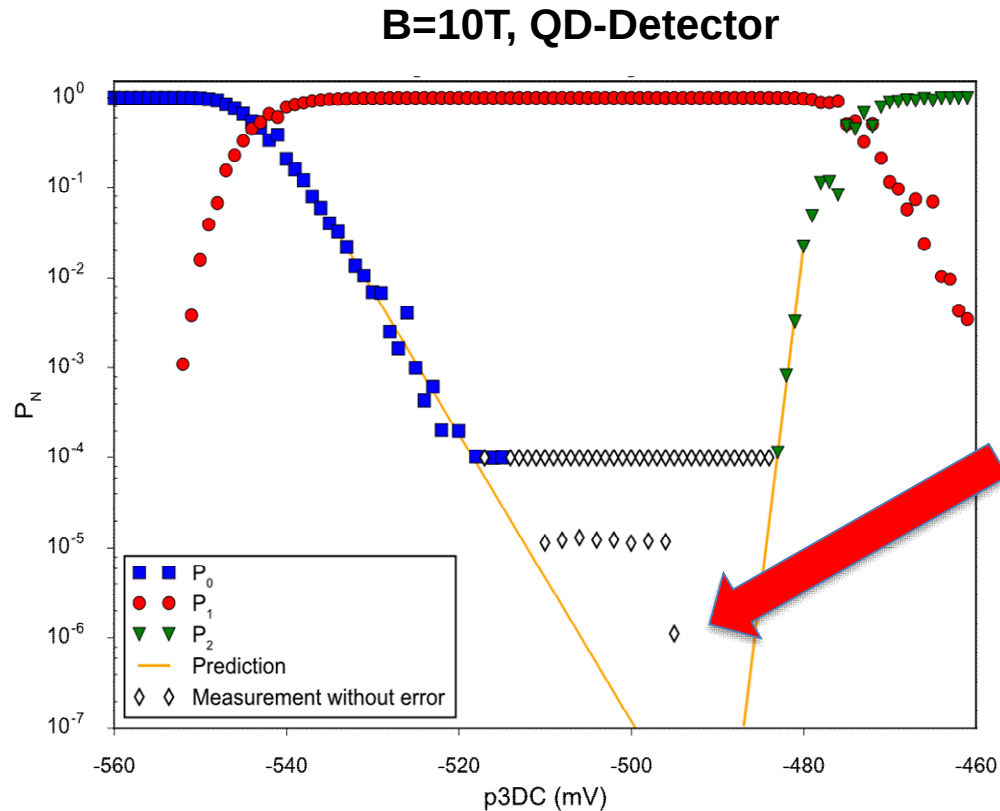


Single electron detection



Counting statistics of pumping



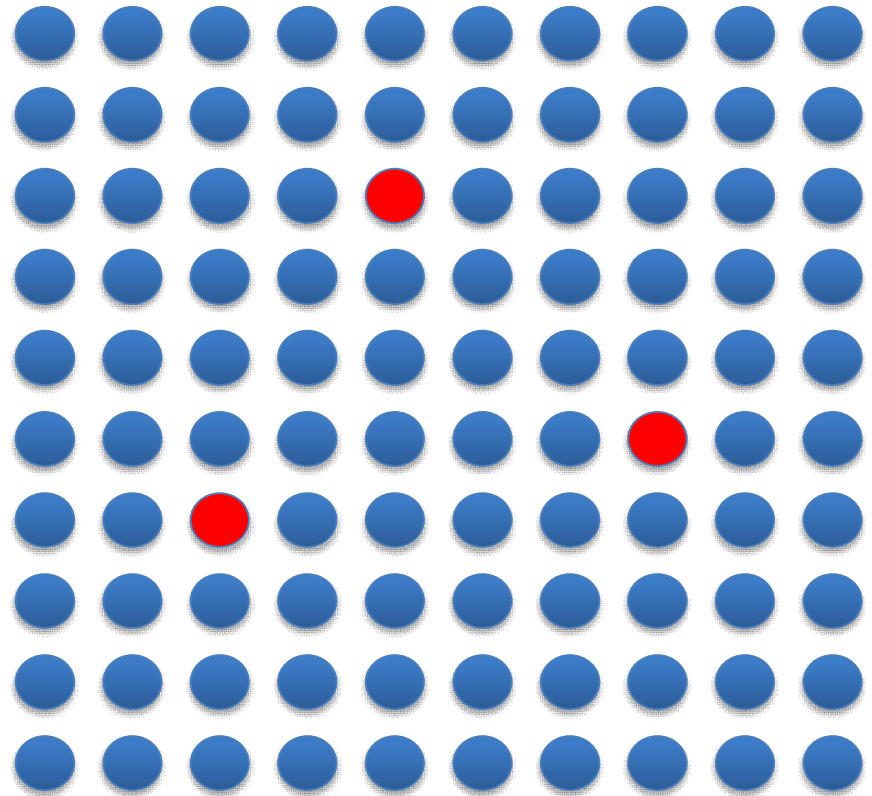


- No error after 10^6 pump cycles at $B = 10T$; $f = 50$ MHz
- Measurement limited by slow acquisition (1-2 days for 10^6)
- Ongoing: develop faster RF-SET detectors → better validation

- Validate single electron current by single-electron detectors

- about 5×10^8 electrons/s
- about 100 - 1000 errors/s
- what to count?

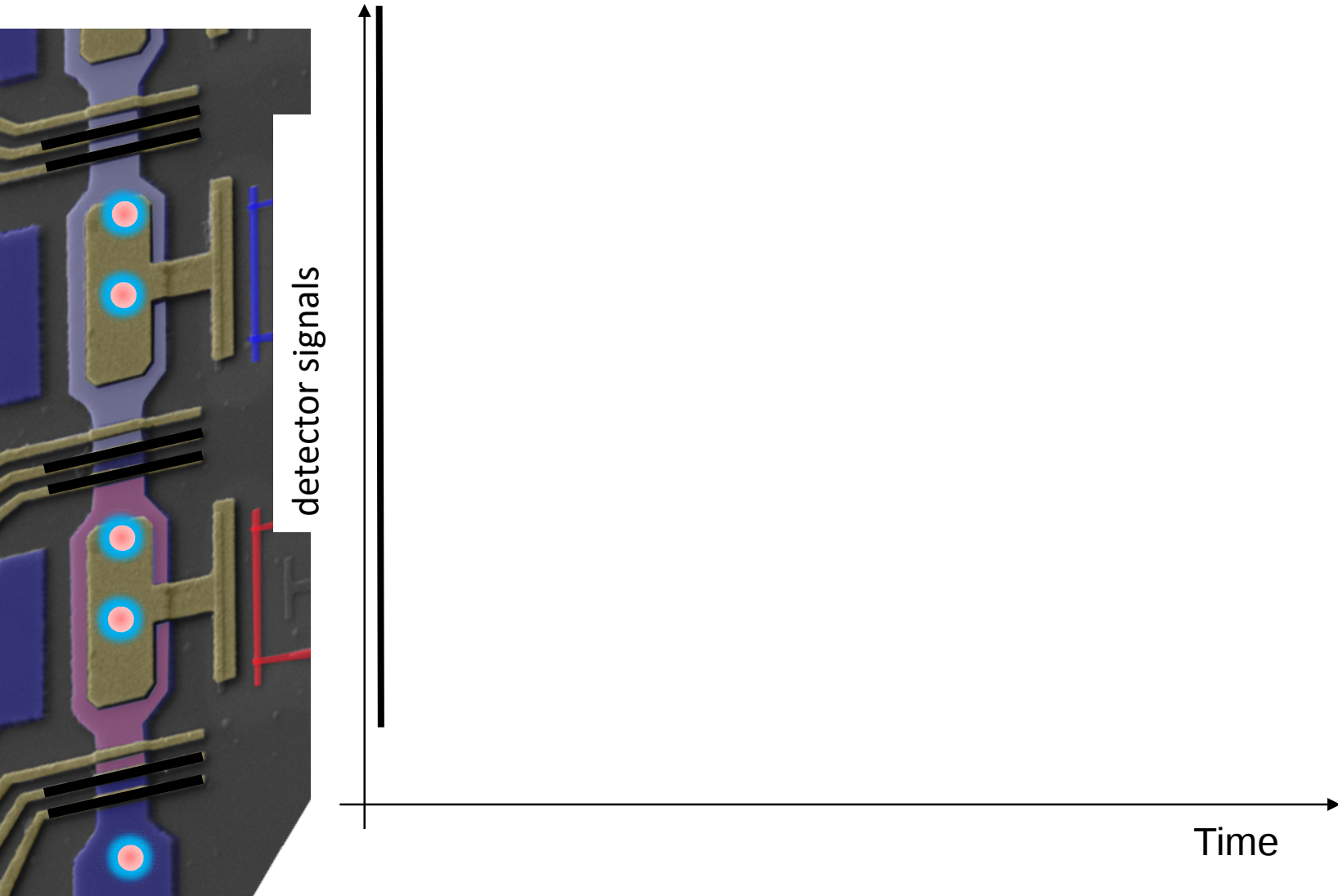
- **Count the errors!**



In-situ error detection

No errors:

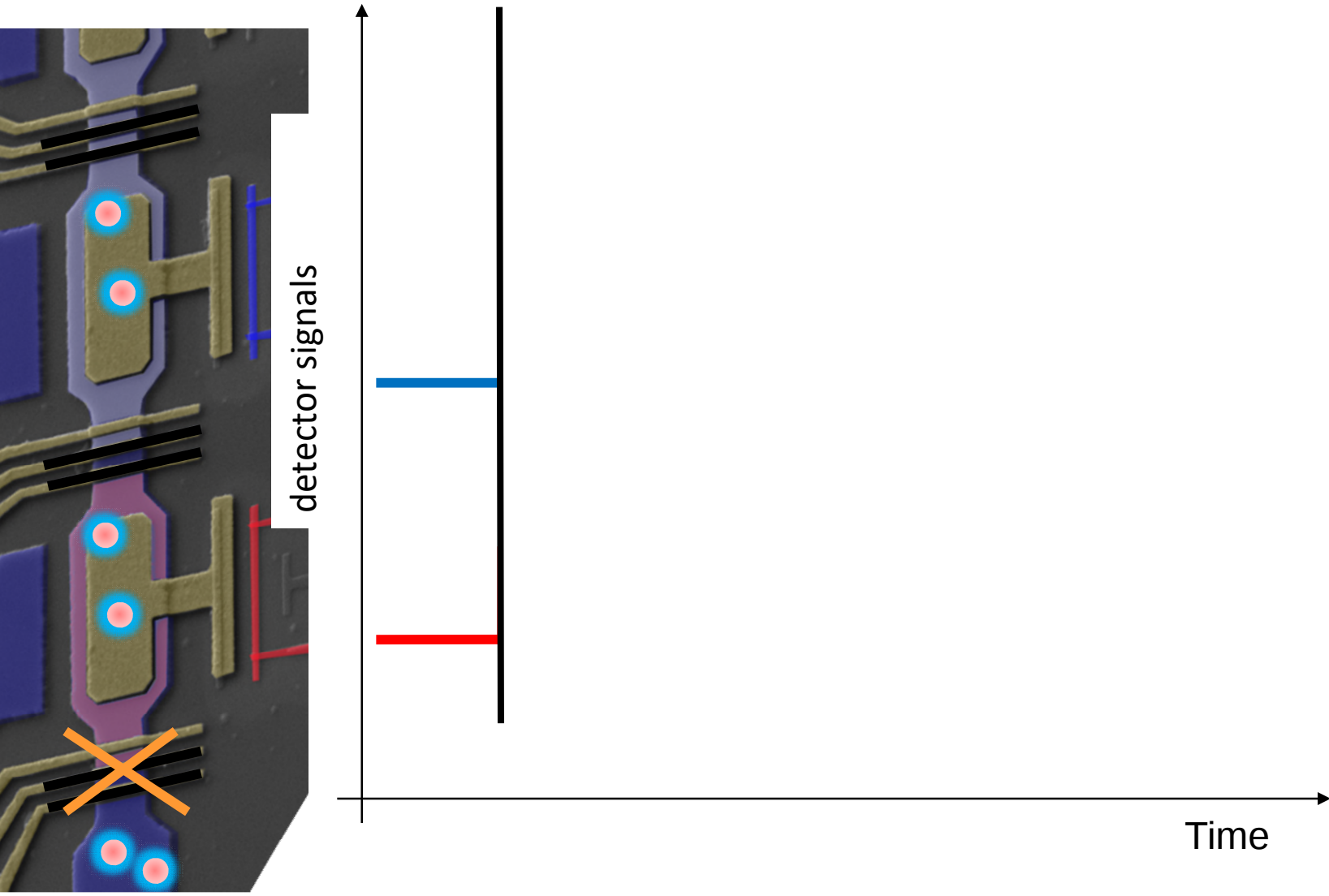
Constant detector signal



In-situ error detection

Fehler P1:

D1: 1 one electron less

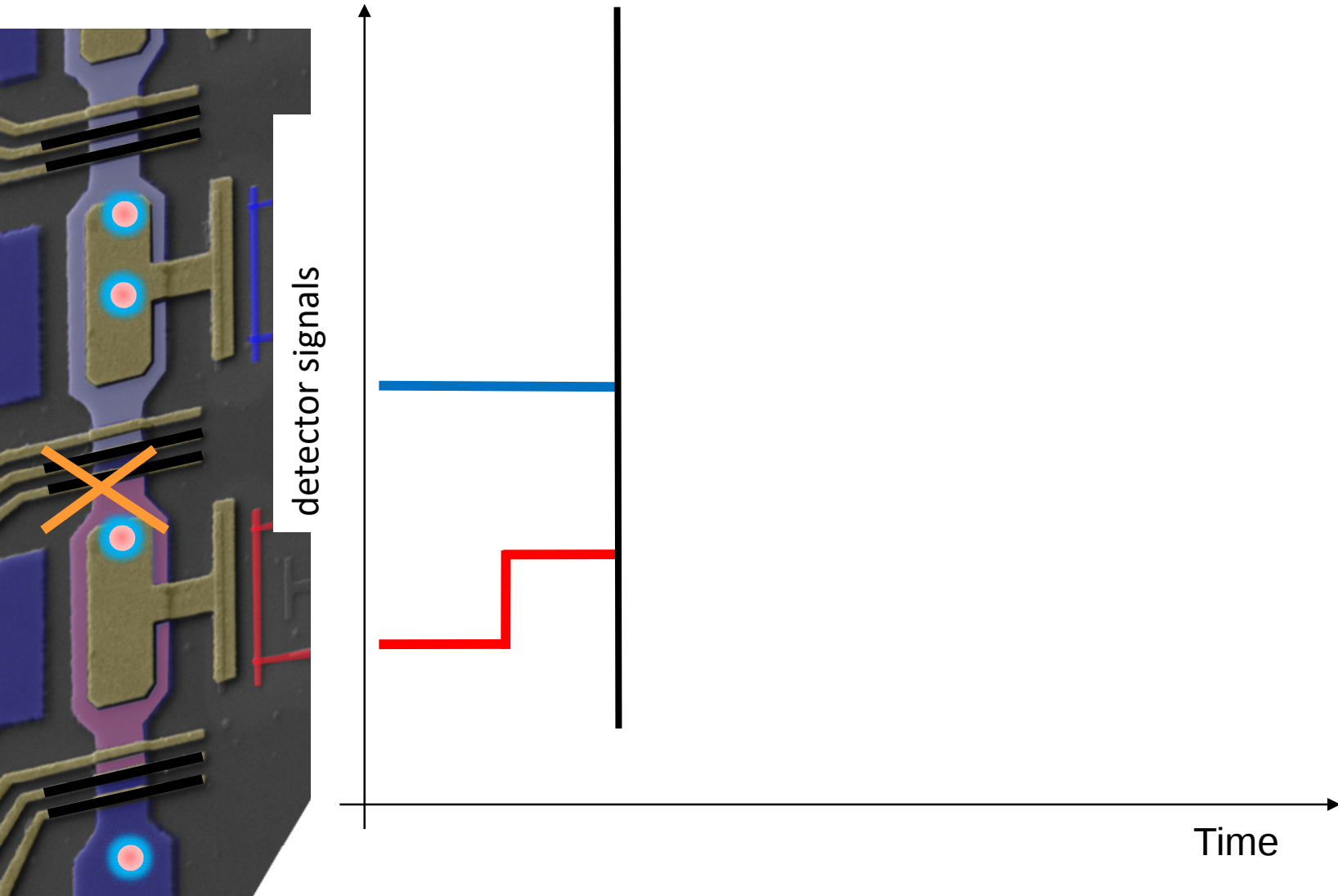


In-situ error detection

Error P2:

D1: one electron more

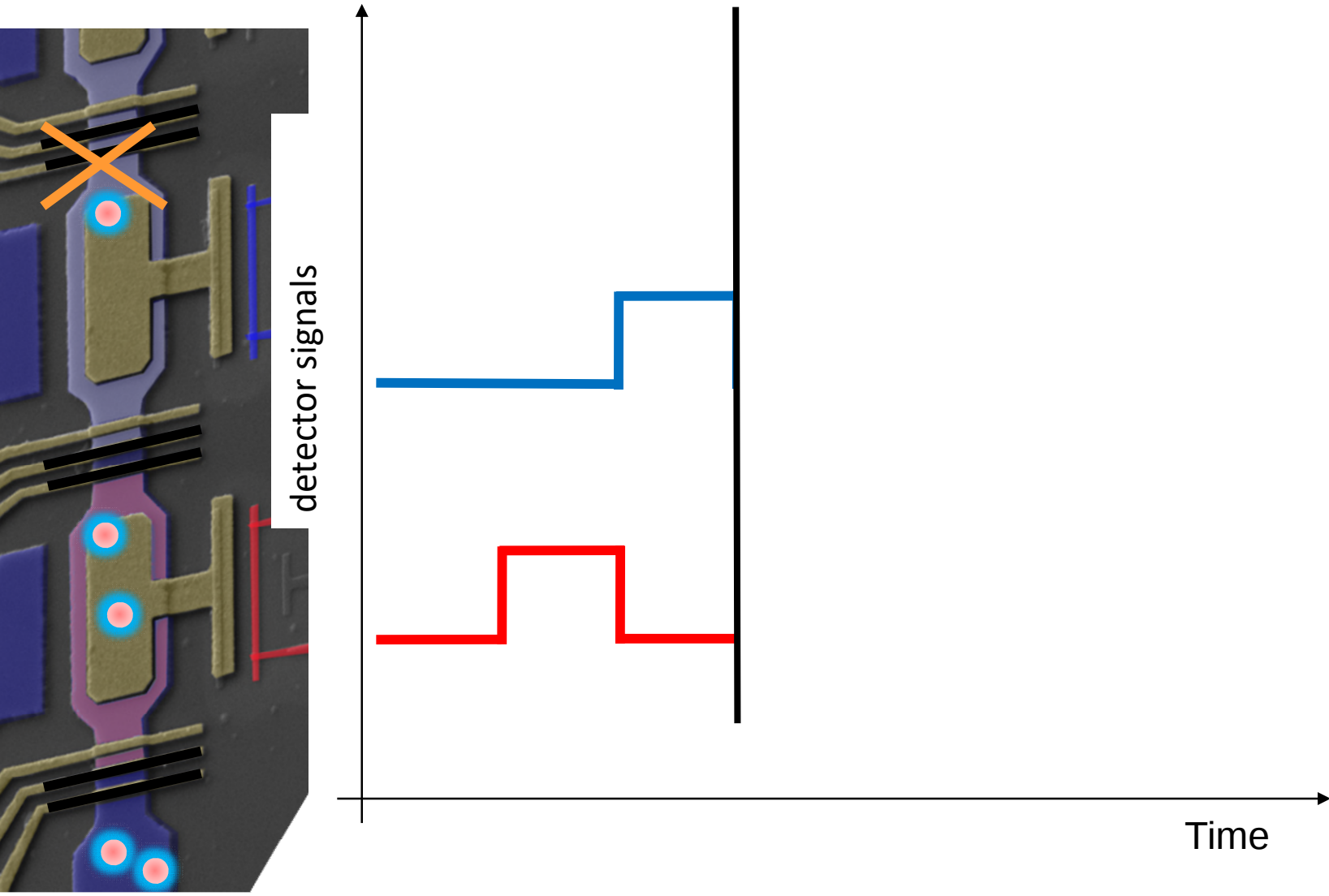
D2: one electron less



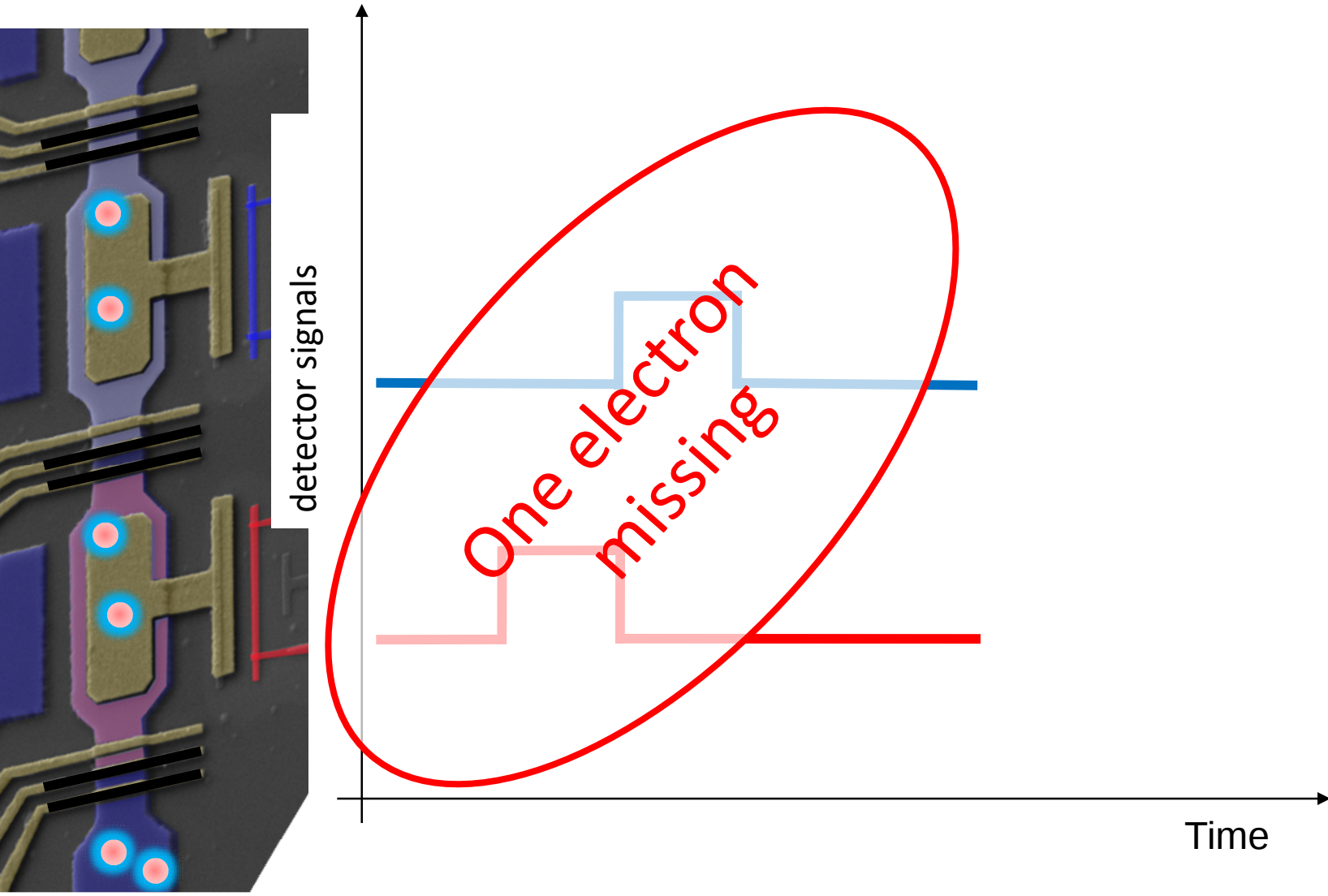
In-situ error detection

Error P3:

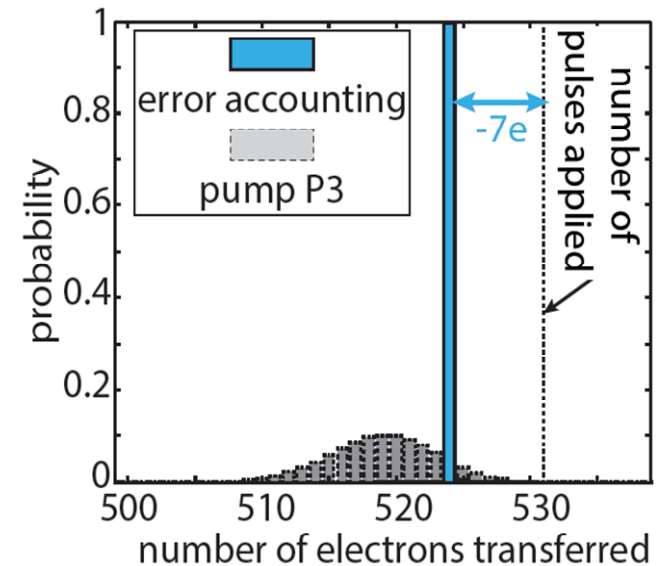
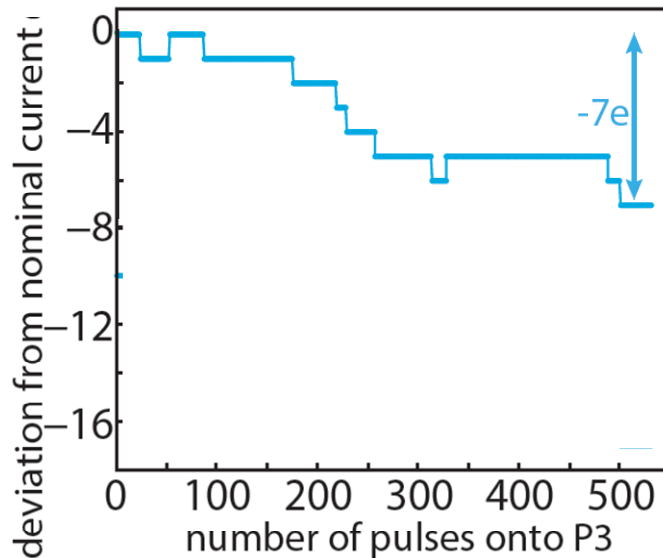
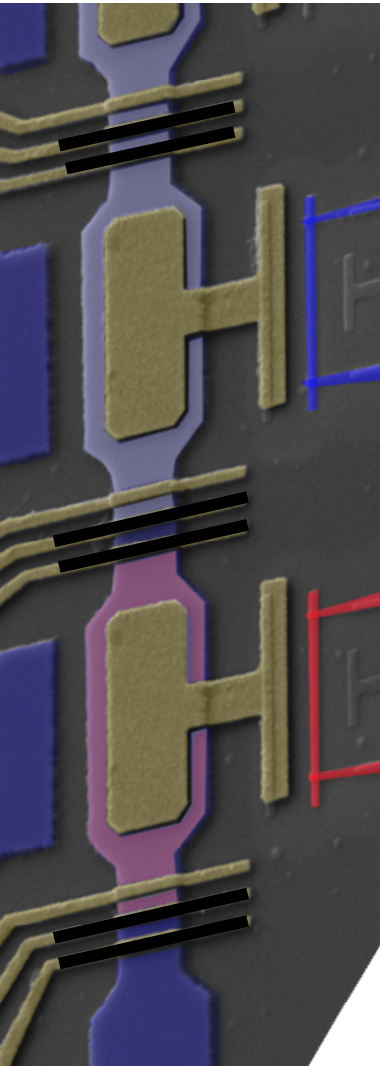
D2: one electron more



In-situ error detection

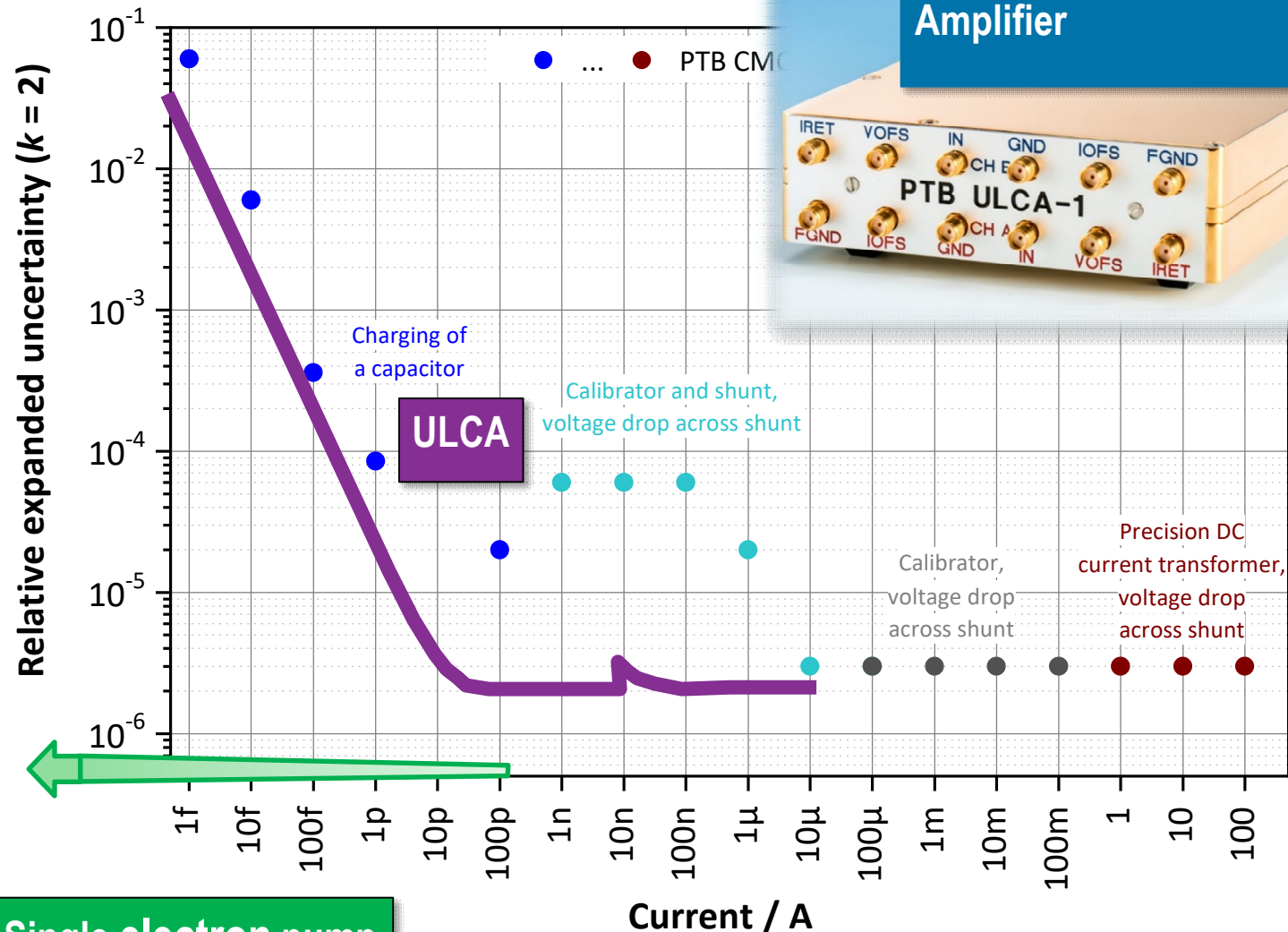


Statistic analysis of current uncertainty



- Self referenced quantized current source
- Uncertainty reduced by factor of 50
- At few aA current amplitudes

DC Current Metrology: Present & Future



Ultra-Low Noise Current Amplifier



- Realization of the ampere by pumping electrons
 $u = 1.6 \cdot 10^{-7}$ at 100 pA
- Single electron detection
 ➔ single electron counting
- In situ validation of single electron pumps
- Counting electrons is a tool for ultimate low current metrology

Thanks to

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